RADIATION TEST REPORT

PRODUCT:	REF02AZQMLR
MASK:	
FILE:	
DATE CODE:	
GAMMA:	0,100K
GAMMA SOURCE:	Co60
DOSE RATE:	38.93 rad/sec
FACILITIES:	National Semiconductor Santa Clara, Ca.
TESTED:	26-Jan-05

The RADTEST℠ DATA SERVICE is a compilation of radiation test results on Analog Devices' Space grade products. It is designed to assist customers in selecting the right product for applications where radiation is a consideration. Many products manufactured by Analog Devices, Inc. have been shown to be radiation tolerant to most tactical radiation environments, Analog Devices , Inc. does not make any claim to maintain or guarantee these levels of radiation tolerance without lot qualification test.

It is the responsibility of the Procuring Activity to screen products from Analog Devices, Inc. for compliance to Nuclear Hardness Critical Items (HCI) specifications.

WARNING:

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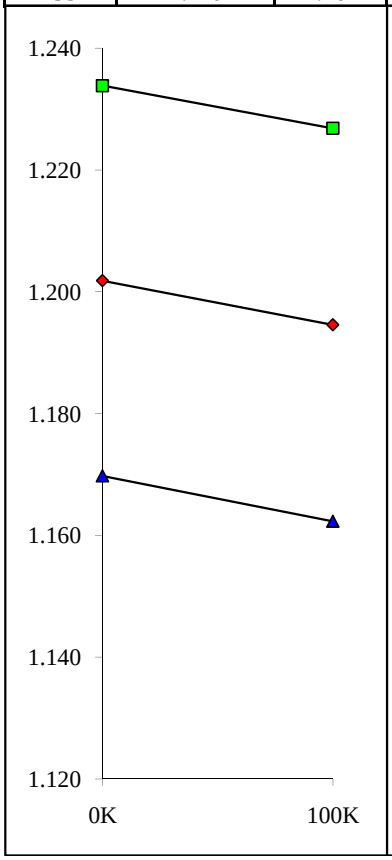
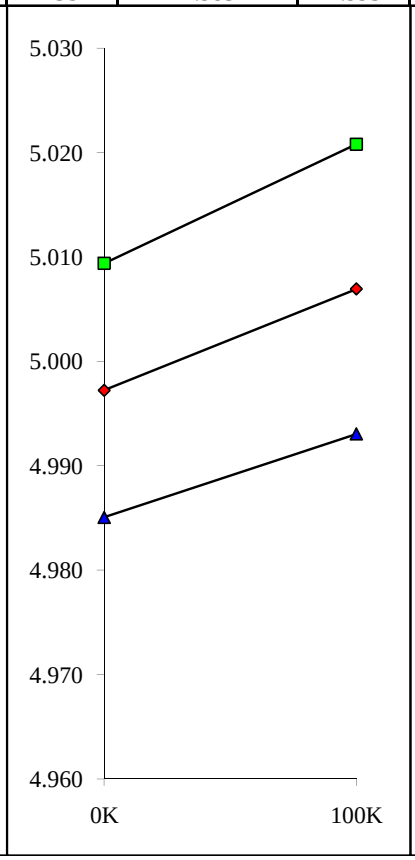
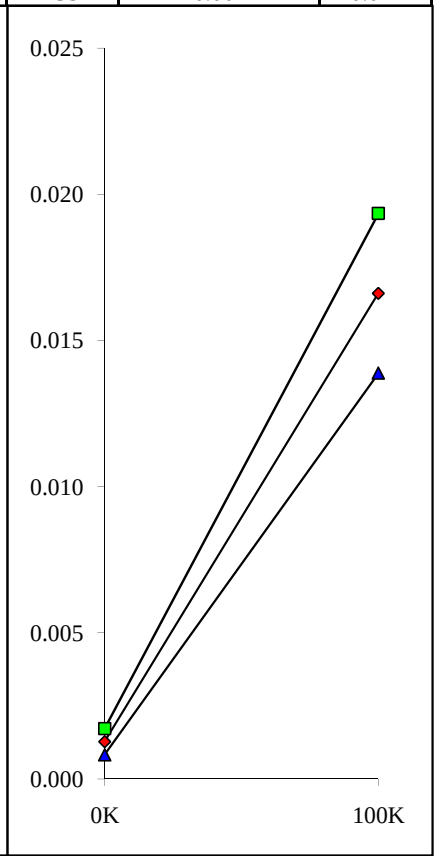
ANALOG DEVICES

T#1.0	ISY ,Vin=15V	mA	T# 2.0	VOUT @Vin=15V	V	T# 3.0	LN.REG 8V TO 33V	%/V
SN	0K	100K	SN	0K	100K	SN	0K	100K
1	1.190	1.192	1	4.996	4.996	1	0.001	0.001
2	1.199	1.194	2	5.002	5.008	2	0.002	0.017
3	1.181	1.175	3	4.990	4.996	3	0.001	0.018
4	1.205	1.188	4	5.001	5.008	4	0.001	0.016
5	1.185	1.178	5	4.996	5.007	5	0.001	0.018
26	1.208	1.195	26	5.002	5.014	26	0.002	0.015
27	1.212	1.199	27	4.996	5.008	27	0.002	0.016
28	1.196	1.186	28	4.997	5.008	28	0.001	0.016
29	1.194	1.188	29	4.995	5.002	29	0.001	0.016
51	1.208	1.200	51	4.996	5.002	51	0.001	0.016
52	1.209	1.199	52	4.990	5.002	52	0.001	0.015
53	1.212	1.199	53	4.996	5.002	53	0.001	0.017
54	1.211	1.205	54	5.002	5.010	54	0.001	0.016
76	1.199	1.195	76	4.996	5.008	76	0.001	0.016
77	1.190	1.185	77	4.996	5.008	77	0.001	0.016
78	1.183	1.181	78	4.992	5.002	78	0.001	0.017
79	1.198	1.189	79	4.996	5.008	79	0.001	0.016
101	1.207	1.208	101	5.002	5.010	101	0.001	0.018
102	1.213	1.208	102	5.002	5.012	102	0.001	0.017
103	1.213	1.209	103	4.996	5.008	103	0.001	0.018
104	1.213	1.211	104	5.002	5.014	104	0.001	0.018
min	1.181	1.175	min	4.990	4.996	min	0.001	0.015
max	1.213	1.211	max	5.002	5.014	max	0.002	0.018
stdev	0.011	0.011	stdev	0.004	0.005	stdev	0.000	0.001
average	1.202	1.195	average	4.997	5.007	average	0.001	0.017
+3S	1.234	1.227	+3S	5.009	5.021	+3S	0.002	0.019
-3S	1.170	1.162	-3S	4.985	4.993	-3S	0.001	0.014







T# 4.0	LD. REG 0 TO 10mA	%/mA
SN	0K	100K
1	0.003	0.003
2	0.003	0.004
3	0.004	0.004
4	0.003	0.003
5	0.004	0.004
26	0.003	0.004
27	0.003	0.003
28	0.003	0.003
29	0.004	0.004
51	0.003	0.003
52	0.003	0.004
53	0.003	0.003
54	0.003	0.004
76	0.003	0.003
77	0.003	0.004
78	0.003	0.004
79	0.003	0.003
101	0.003	0.003
102	0.003	0.004
103	0.003	0.004
104	0.003	0.004
min	0.003	0.003
max	0.004	0.004
stdev	0.000	0.000
average	0.003	0.004
+3S	0.004	0.004
-3S	0.003	0.003